

MS1307

N-channel power MOS FET transistor commonly used in RF applications around 26-30 MHz. TO220 package.



The exact specification is unknown but should be equivalent and very close to the following:

Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	9.7	A
$I_D @ T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	6.8	
I_{DM}	Pulsed Drain Current	38	
$P_D @ T_C = 25^\circ\text{C}$	Power Dissipation	48	W
	Linear Derating Factor	0.32	W/ $^\circ\text{C}$
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}	Single Pulse Avalanche Energy	91	mJ
I_{AR}	Avalanche Current	5.7	A
E_{AR}	Repetitive Avalanche Energy	4.8	mJ
dv/dt	Peak Diode Recovery dv/dt	5.0	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	$^\circ\text{C}$
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf·in (1.1N·m)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	3.1	$^\circ\text{C}/\text{W}$
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	62	

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.11	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	0.20	Ω	$V_{GS} = 10\text{V}, I_D = 5.7\text{A}$
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	2.7	—	—	S	$V_{DS} = 50\text{V}, I_D = 5.7\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}, T_J = 150^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{GS} = -20\text{V}$
Q_g	Total Gate Charge	—	—	25	nC	$I_D = 5.7\text{A}$
Q_{gs}	Gate-to-Source Charge	—	—	4.8		$V_{DS} = 80\text{V}$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	11		$V_{GS} = 10\text{V}$
$t_{d(on)}$	Turn-On Delay Time	—	4.5	—	ns	$V_{DD} = 50\text{V}$
t_r	Rise Time	—	23	—		$I_D = 5.7\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	32	—		$R_G = 22\Omega$
t_f	Fall Time	—	23	—		$R_D = 8.6\Omega$
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	330	—	pF	$V_{GS} = 0\text{V}$
C_{oss}	Output Capacitance	—	92	—		$V_{DS} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	54	—		$f = 1.0\text{MHz}$

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	9.7	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode)	—	—	38		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	$T_J = 25^\circ\text{C}, I_S = 5.7\text{A}, V_{GS} = 0\text{V}$
t_{rr}	Reverse Recovery Time	—	99	150	ns	$T_J = 25^\circ\text{C}, I_F = 5.7\text{A}$
Q_{rr}	Reverse Recovery Charge	—	390	580	nC	di/dt = 100A/ μs